

## Stable, High Efficiency White Electrophosphorescent Organic Light Emitting **Diodes (OLED) by Reduced Molecular Dissociation (DE-EE0007077)**

Principal Investigator Collaborators

	- P	roject o	verviev	N				
<ul> <li>Project objectives</li> <li>Development of long-lived and efficient blue PHOLED</li> <li>Introduce highly excited state manager into blue PHOLED to recycle multiply excited triplets and/or charges for emission</li> </ul>								
•	mplement R+G+B stacked white PHOLED							
@1000nits	blue PHOLED Current	Target	@1000nits	Y2 goal for white PHOLED @1000nits Current				
EQE [%]	9.5 (18.0)	> 15	η [lm/W]	49 (47)	Target 70			
	[0.16, 0.31]	[0.15, 0.30]	LT70 [hr]	4,000 (13,00	-			
LT70 [hr]	486 (*1,300)	3,000	CT [K]	2580 (278)	,			
Size [cm <sup>2</sup> ]	0.02	1	CRI	83 (89)	85			
		renthesis: stacked. Parenthesis: stacked.						
•	sk summar							
Task		J Task title		Targe	t Q Status			
	able blue phos		st materials	Idige				
	ficient blue phos		St materials	1	Complete			
	gh energy electro	4	Complete					
	atched host and	. 4	Complete					
	ng-lived blue PF	8	Complete					
	ue PHOLED: eff.	_	Passed					
	cited state sink		Complete					
	evelopment of ex	2	- · ·					
	Employing excited state sinks blue PHOLEDs				Complete			
	aterials and devi	7	Complete					
	G/NG2 Blue PHOLED: 2x lifetime by excited state sink				Passed			
	Lifetime validation and scaling				3 Complete			
<ul> <li>Project Roles</li> <li><u>UM</u>: Device physics and characterization</li> <li><u>USC</u>: Material synthesis and analysis</li> <li><u>UDC</u>: Panel fabrication, validation and scaling</li> </ul>								
<ul> <li><u>Requirements: High performance WOLEDs</u></li> </ul>								
<ul> <li>Lifetime</li> <li>Reduced blue intrinsic degradation</li> <li>Stable green blocking layer</li> <li><u>CRI</u></li> <li>3 emitter balanced emission spectrum</li> <li>Balanced exciton profile &amp; emitter degradation rates</li> </ul>								

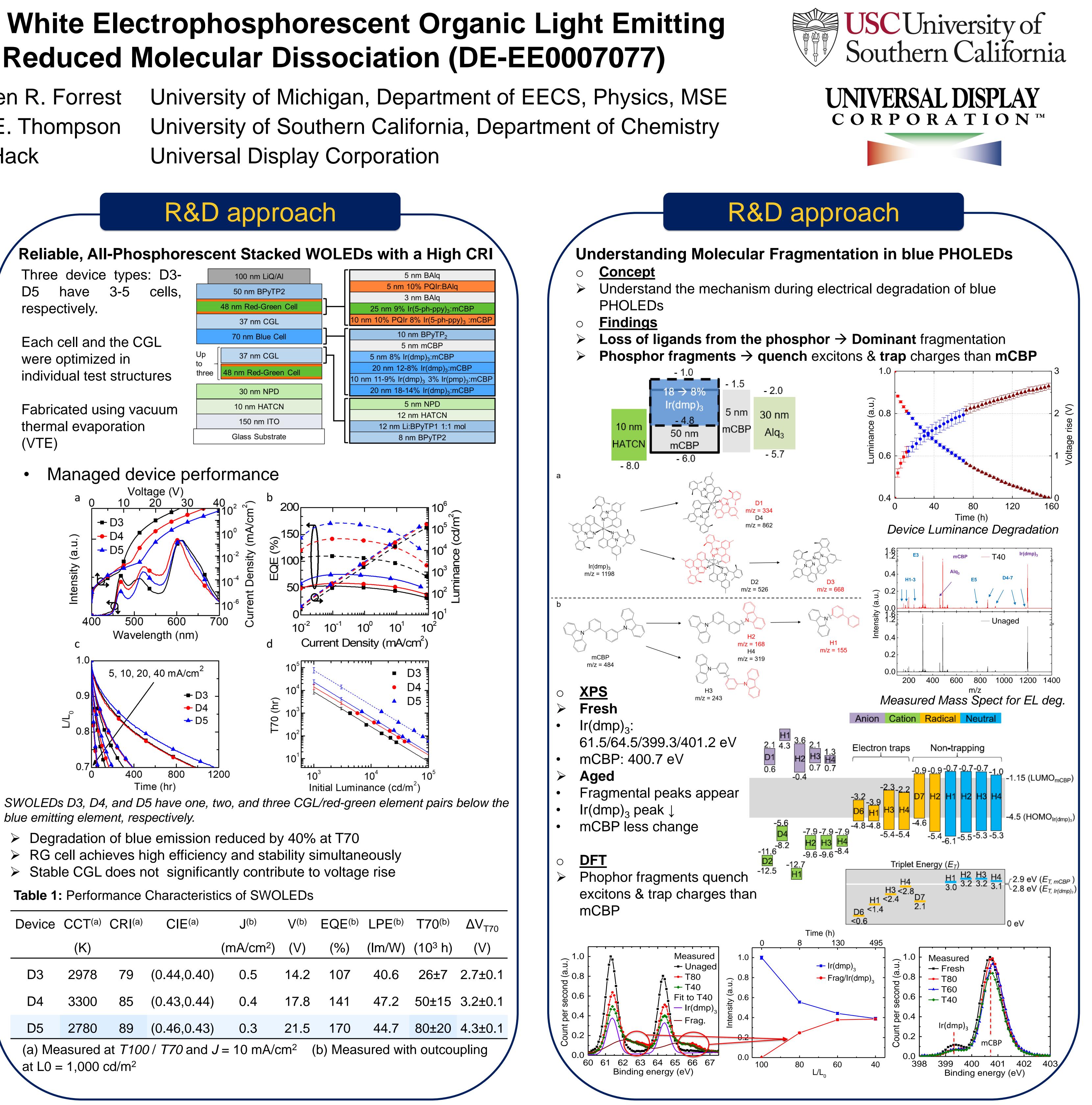
Dr. Stephen R. Forrest Dr. Mark E. Thompson Dr. Mike Hack

**Universal Display Corporation** 

Three device types: D3have D5 respectively.

Each cell and the CGL were optimized in individual test structures

Fabricated using vacuum thermal evaporation (VTE)



blue emitting element, respectively.

Device	CCT <sup>(a)</sup>	CRI <sup>(a)</sup>	CIE <sup>(a)</sup>	၂(b)		
	(K)			(mA/cm <sup>2</sup> )		
D3	2978	79	(0.44,0.40)	0.5		
D4	3300	85	(0.43,0.44)	0.4		
D5	2780	89	(0.46,0.43)	0.3		
(a) Measured at T100 / T70 and $J = 10$ mA/						

at  $L0 = 1,000 \text{ cd/m}^2$